

#510
KWS
D-26-01
PATENT APPLICATION

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

In re application of

Hiroki KOIKE

Appln. No.:

Group Art Unit: Unknown

Confirmation No.:

Examiner: Unknown

Filed: April 4, 2001

For: SEMICONDUCTOR MEMORY DEVICE AND TESTING SYSTEM AND TESTING
METHOD

PRELIMINARY AMENDMENT

Commissioner for Patents
Washington, D.C. 20231

Sir:

Prior to examination, kindly amend the above-identified application as follows:

IN THE SPECIFICATION:

Page 21, paragraph 4

a1
Figures 3(a) and 3(b) show illustrations for describing problems that conventional
ferroelectric memories have.

Page 22, paragraph 2

a2
Figures 11(a) and 11(b) show circuit diagrams illustrating example arrangements of a
sample hold circuit according to embodiment 2 of the invention (where the circuit is provided for
one bit-line).